

Two different groups of info

➤ Quantitative information: Intensity of luminescence signal, signal integrals, sensitization (**quantifying TL**)

➤ Qualitative information = **Characteristics of the TL peak for understanding the mechanism as well as for assessing the lifetime of each trap**
Activation energy, frequency factor, order of kinetics → **towards estimating the life time of each trap**

Activation energy: definition

Activation energy (definition and properties)

It is the energy, E , expressed in eV, assigned to a **metastable state** or level within the forbidden band gap between the **conduction band (CB)** and the **valence band (VB)** of a crystal. This energy is also called trap depth. The metastable level can be an electron trap, near to the CB, or a hole trap, near the VB, or a **luminescence centre**, more or less in the middle of the band gap. The metastable levels are originated from **defects** of the crystal structure. A crystal can contain several kinds of traps and luminescence centers. If E is such that $E > \text{several } kT$, where k is the Boltzmann's constant, then the trapped charge can remain in the trap for a long period. For an electron trap, E is measured, in eV, from the trap level to the bottom of the CB. For a hole trap, it is measured from the trap to the top of the VB.

Handbook of thermoluminescence, C. Furetta

Frequency Factor: definition

The frequency factor, s , is known as the attempt-to-escape frequency and is interpreted as the number of times per second, ν , that an electron interacts with the crystal lattice of a solid, multiplied by a transition probability κ , multiplied by a term which accounts for the change in entropy ΔS associated with the transition from a trap to the delocalized band. s may be written as

$$s = \nu \cdot \kappa \cdot \exp\left(\frac{\Delta S}{k}\right)$$

where k is the Boltzmann constant [1,2].

The expected maximum value of s should be similar to the lattice vibrational frequency (Debye frequency), i.e. $10^{12} - 10^{14} \text{ s}^{-1}$. According to Chen, the possible range for s is from 10^5 to 10^{13} s^{-1} [3].

Methods for determining E

More in detail, it is possible to group these methods in main sections:

- a) Methods based upon maximum temperatures,
- b) Methods based upon low temperatures side analysis,
- c) Variable heating rates methods,
- d) Area measurements methods,
- e) Isothermal decay method,
- f) Inflection points method,
- g) Peak shape geometrical methods.

a) The simplest procedure is that searching for a linear relationship between glow temperature and activation energy. → First order of kinetics → Requires knowledge of s .

b) E value independent on s . Thermal quenching and temperature lag could result in underestimation → *Low β*

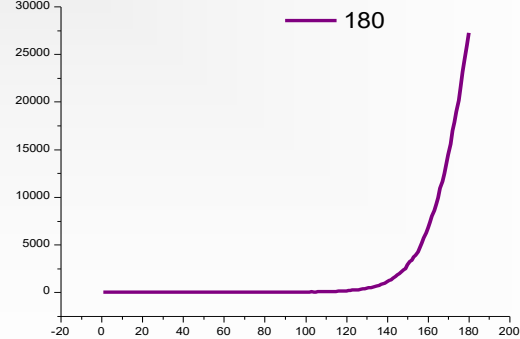
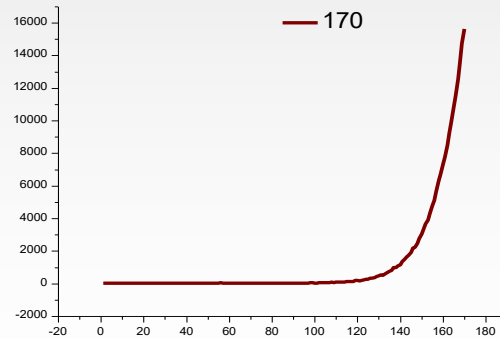
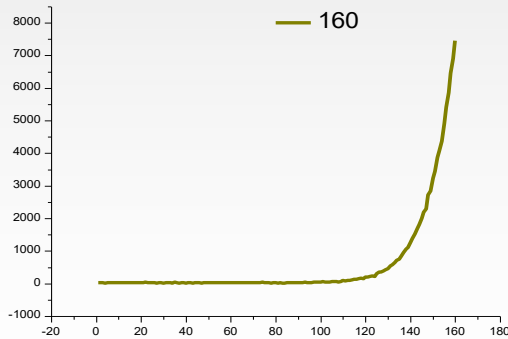
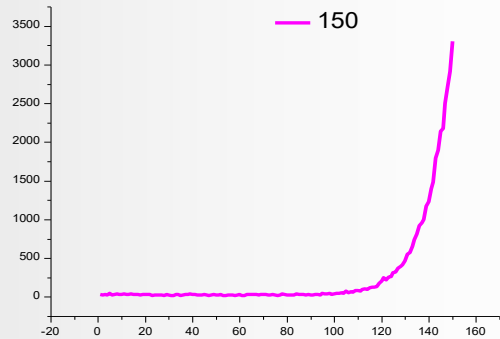
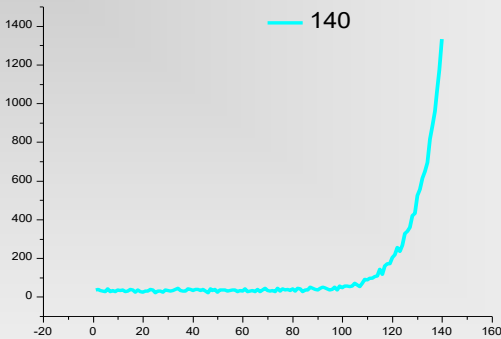
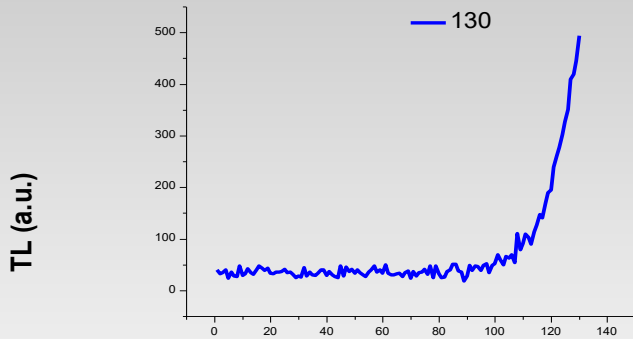
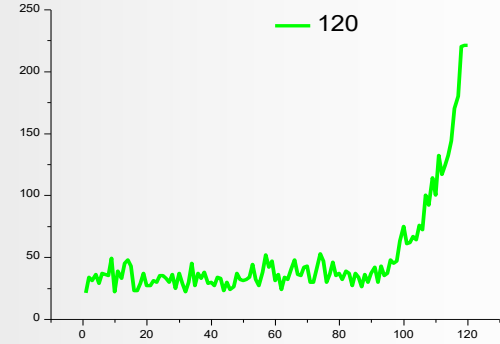
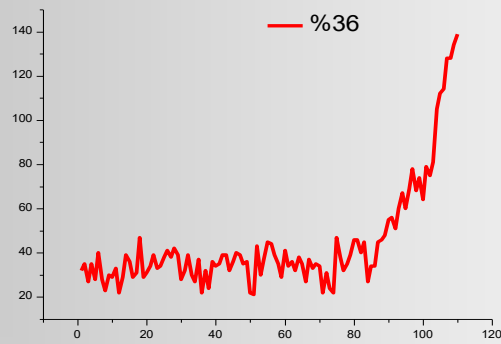
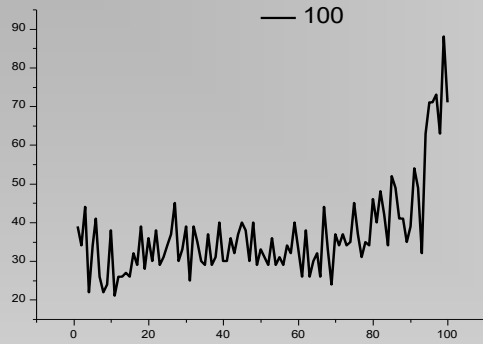
c) E value not affected by thermal quenching but s value is some affected → *Low β is suggested*

5 different methods for E

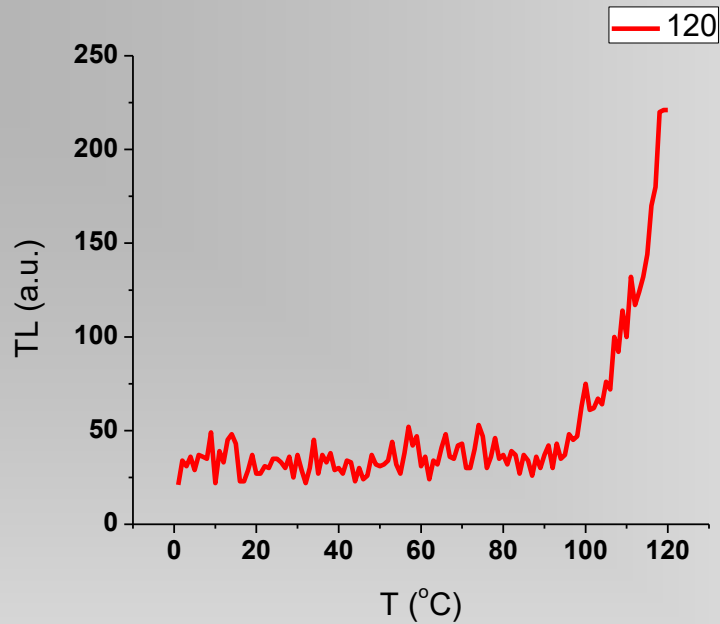
- De-convolution (***both quantitative and qualitative info***)
- Initial rise technique
- Fractional glow technique
- Various heating rates method (***Check for thermal quenching first***)
- ***Isothermal decay***

$$\tau = s^{-1} \exp\left(\frac{E}{kT}\right)$$

Fractional glow



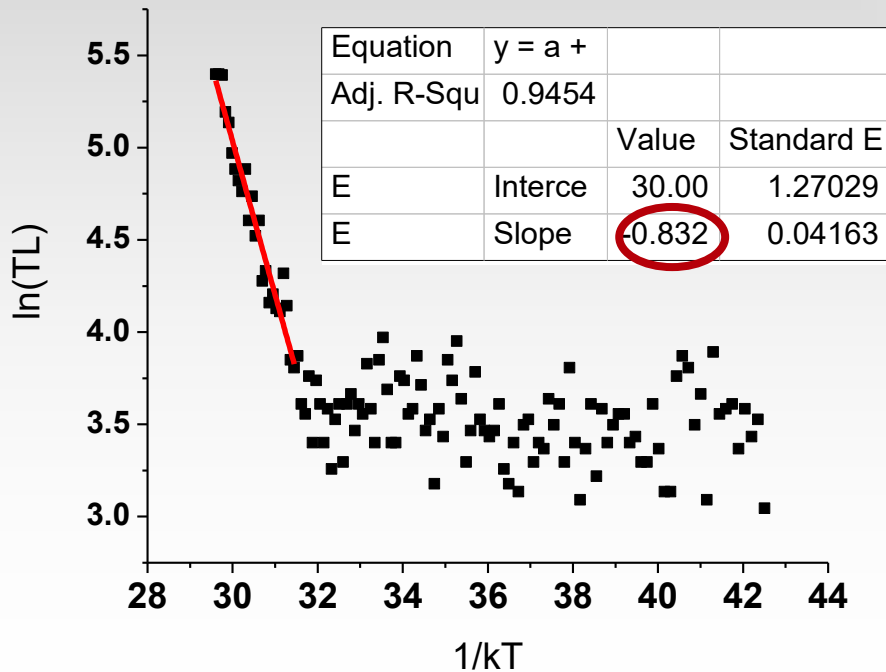
Temperature (°C)



**Initial part:
Boltzmann factor
→ Initial Rise Technique**

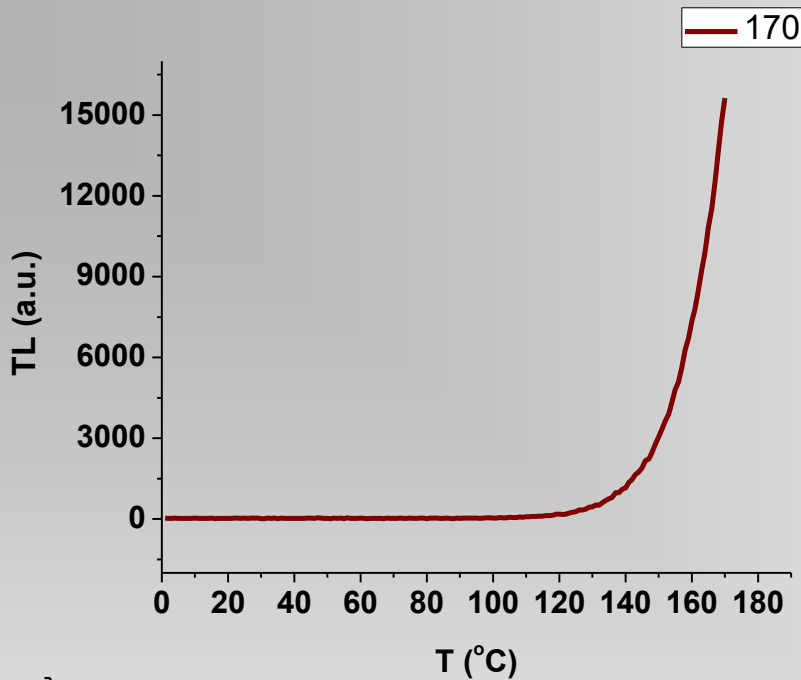
$$I \propto T^{\alpha} \exp\left(-\frac{E}{kT}\right)$$

$$\ln I = \alpha \ln T - \frac{E}{kT}$$



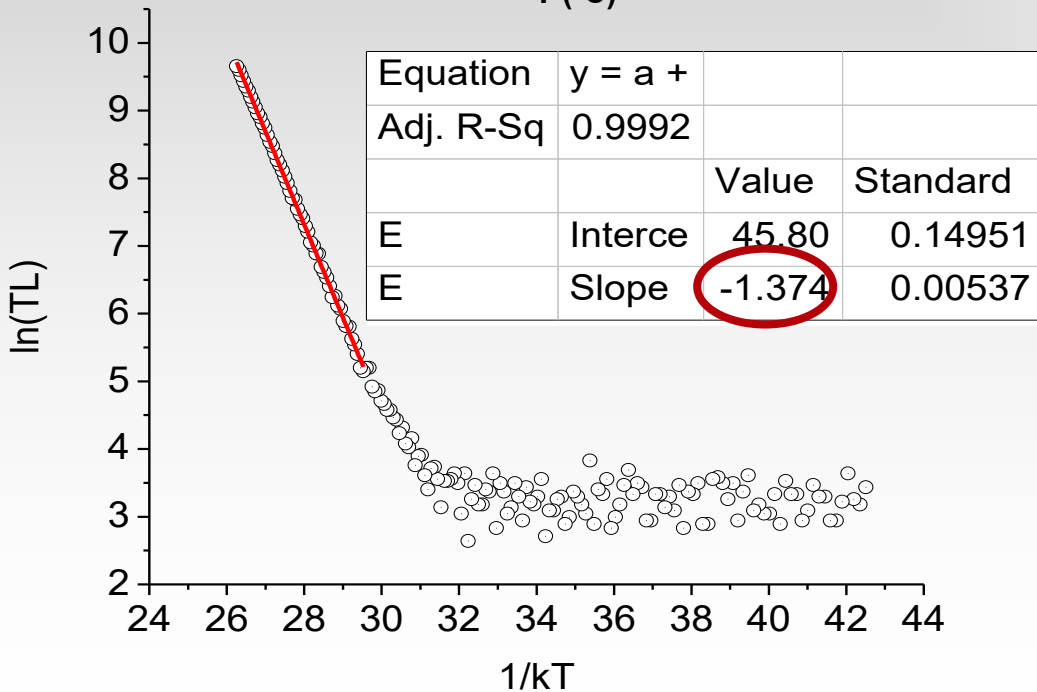
Arrhenius plot

**Initial part:
Boltzmann factor
→ Initial Rise Technique**



$$I \propto T^\alpha \exp\left(-\frac{E}{kT}\right)$$

$$\ln I = \alpha \ln T - \frac{E}{kT}$$



**Arrhenius plot
Intercept ~ ln(s)**

Arrhenius equation

The Arrhenius equation gives the mean time, τ , that an electron spends in a trap at a given temperature T . It is

$$\tau = s^{-1} \exp\left(\frac{E}{kT}\right) \quad (1)$$

where s is the frequency factor (in the case of thermoluminescence the frequency factor is also called attempt-to-escape frequency), E is the energy difference between the bottom of the CB and the trap position in the band gap, also called trap depth or activation energy, k is the Boltzmann's constant.

Equation (1) can be rewritten as

$$p = \tau^{-1} \quad (2)$$

which gives the probability p , per unit of time, of the release of an electron from the trap.

$$s = \frac{\beta \cdot E}{k \cdot T_M^2} \exp\left(\frac{E}{kT_M}\right) \quad [\text{sec}^{-1}]$$

First order

$$s = \frac{\beta E \exp\left(\frac{E}{kT_M}\right)}{kT_M^2} \left[1 + \frac{2kT_M}{E}\right]^{-1}$$

Second order

$$s = \left[\frac{kT_M^2 \exp\left(-\frac{E}{kT_M}\right)}{\beta E} \left(1 + \frac{2kT_M(b-1)}{E}\right) \right]^{-1}$$

General order

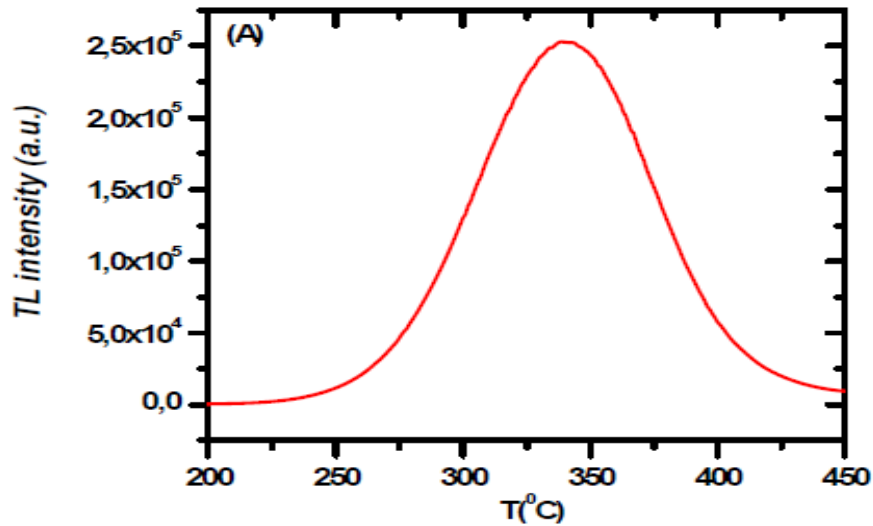


Fig.

1A: Natural TL (NTL) glow curve signal of obsidian

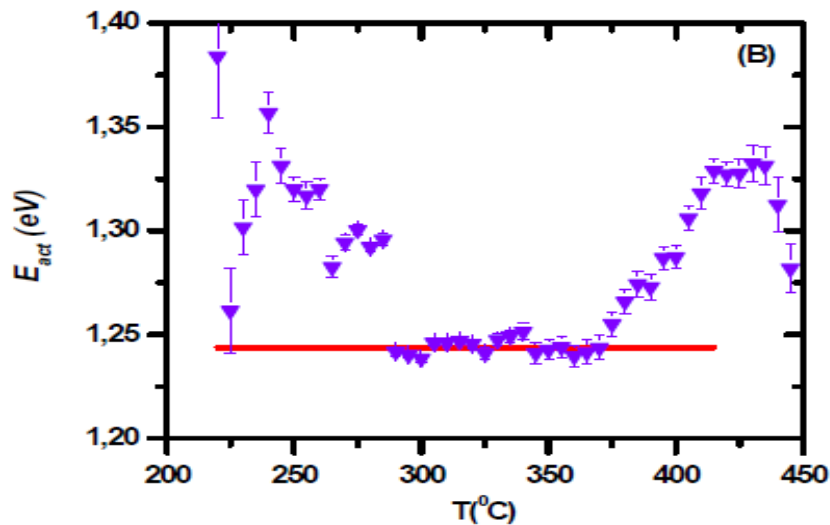


Fig. 1B: Initial rise (I.r.) plot for the NTL signal of obsidian. For both figures, the heating rate applied was 1 °C/s.

**Initial part:
Boltzmann factor
→ Initial Rise Technique**

$$I \propto T^\alpha \exp\left(-\frac{E}{kT}\right)$$

$$\ln I = \alpha \ln T - \frac{E}{kT}$$

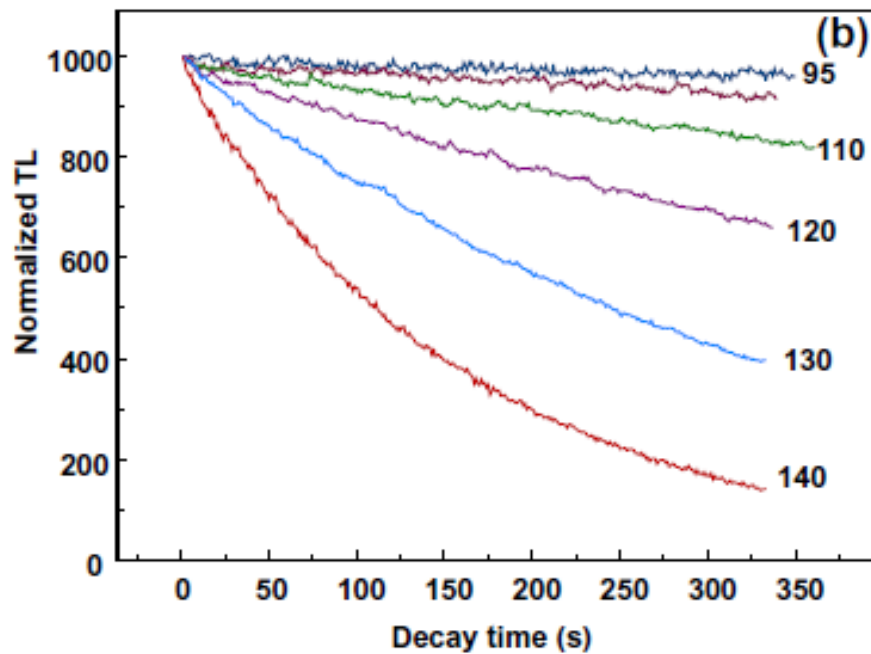
T in units of Kelvin

Isothermal decay

First order

$$I(t) = I_0 \exp(-tp),$$

Measurements in various Temperatures



$$\ln\left(\frac{S_{t_1}}{S_0}\right) = -pt_1$$

$$m_i = -s \exp\left(-\frac{E}{kT_i}\right)$$

$$\ln(m_i) = \ln(-s) - \frac{E}{kT_i}$$